



ISC Audits & Reviews SC Summary (March 24th, 2026)

Doc.	Title	Results
7086A;	Revision to SEMI F61–0521, Guide for Design and Operation of a Semiconductor Ultrapure Water System, with title change to: Guide for Design, Construction, Installation, and Operation of a Semiconductor Ultrapure Water System;	Passed
7193B;	New Standard: Guide for Substrate Design of Flexible Hybrid Electronics Based on Additive Printing Methods	Passed
7331;	New Standard: Guide for Peel Testing of RDLs and Other Traces Used Within Advanced Packages and Structures ;	Passed
7332;	New Standard: Specification for Large JEDEC™ Tray Stack Loadport ;	Passed
7345A-LI2;	Correct Well-Known Names;	Passed
7370;	Reapproval of SEMI MS13-0221, Guide for Use of Test Patterns for Characterizing a Deep Reactive Ion Etching (DRIE) Process;	Passed
7371A-LI1;	Addition, to EXCEPTION 2 to ¶7.1;	Passed
7371A-LI3;	Addition, to Table A1-1, of a finger pinch symbol and an entrapment symbol. Symbols will be renumbered, serially, during publication ;	Passed
7371A-LI4;	Addition, to Table A1-1, of a shear symbol ;	Passed
7419-LI2;	Add new SEMI E132 SecurityCertificateChanged notification message;	Passed
7425-LI1;	Establish Unique Well-Known Names;	Passed
R7354;	Ratification Ballot, Revision to SEMI E170.1-0520 Specification For SECS-II Protocol For Secured Foundation Of Recipe Management System;	Passed
SEMI E197-0226	Specification for Large Tray Stack FOUP (LTSF) (Type 2 Editorial Changes)	Passed

For more information, please contact the SEMI Standards Engineer/Coordinator.
<http://www.semi.org/standards/contacts>) nearest you.

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